Date Mailed: November 7, 2006

Sheet 1 of 1

FORM 1449*				
INFORMATION DISCLOSURE STATEMENT	Docket Number: 10873.1623USWO	Application Number: 10/522,488		
IN AN APPLICATION	Applicant: SASAKI, et al.			
(Use several sheets if necessary)	Filing Date: January 26, 2005	Group Art Unit: 2811		

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Date Mailed: April 18, 2006

Sheet 1 of 1

FORM 1449* INFORMATION DISCLOSURE STATEMENT	Docket Number: 10873.16231JSWQ	Application Number: 10/522,488		
IN AN APPLICATION	Applicant: SASAKI, et al.			
(Use several sheets if necessary)	Filing Date: January 26, 2005	Group Art Unit: 2811		

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Sheet 1 of 1

FORM 1449\*

## INFORMATION DISCLOSURE STATEMENT

Docket Number: 10873.1623USWO Application Number:

10/522,488

IN AN APPLICATION

Applicant: SASAK1 et al.

Filing Date: January 26, 2005

Group Art Unit: Unknown

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